

AMENDMENTS TO THE CLAIMS

1. (Canceled)

2. (Currently amended) ~~The method of claim 1 wherein the voltage is varied~~

A method of controlling the burning in of at least one I/C chip in a burn in tool, wherein said tool has a device for mounting each chip to be burned in, a power source to supply electrical current to burn in each chip, and a monitor to continuously monitor the temperature value of each chip, comprising the steps of:

continuously monitoring at least one electrical value input to each chip selected from the group of current, voltage and power, and varying the voltage to maintain the current value below a given value.

3. (Currently amended) ~~The method of claim 1 wherein the voltage is varied~~

A method of controlling the burning in of at least one I/C chip in a burn in tool, wherein said tool has a device for mounting each chip to be burned in, a power source to supply electrical current to burn in each chip, and a monitor to continuously monitor the temperature value of each chip, comprising the steps of:

continuously monitoring at least one electrical value input to each chip selected from the group of current, voltage and power, and varying the voltage to maintain the power value below a given value.

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4 - 7 (Canceled)

8. (Currently amended) ~~The tool of claim 7 wherein the voltage is varied~~ A
burn in tool for burning in at least one I/C chip comprising:
a structure for mounting each chip to be burned in;
a power source to supply electrical current to burn in each chip;
a structure for continuously monitoring at least one electrical value input to each chip
selected from the group of current, voltage and power, and
a structure to vary the voltage to maintain the current value below a given value.

9. (Currently amended) ~~The tool of claim 5 wherein the voltage is varied~~ A
burn in tool for burning in at least one I/C chip comprising:
a structure for mounting each chip to be burned in;
a power source to supply electrical current to burn in each chip;
a structure for continuously monitoring at least one electrical value input to each chip
selected from the group of current, voltage and power, and
a structure to vary the voltage to maintain the power value below a given value.

10 - 12 (Canceled)